



# IEEE SW Test Workshop

Semiconductor Wafer Test Workshop

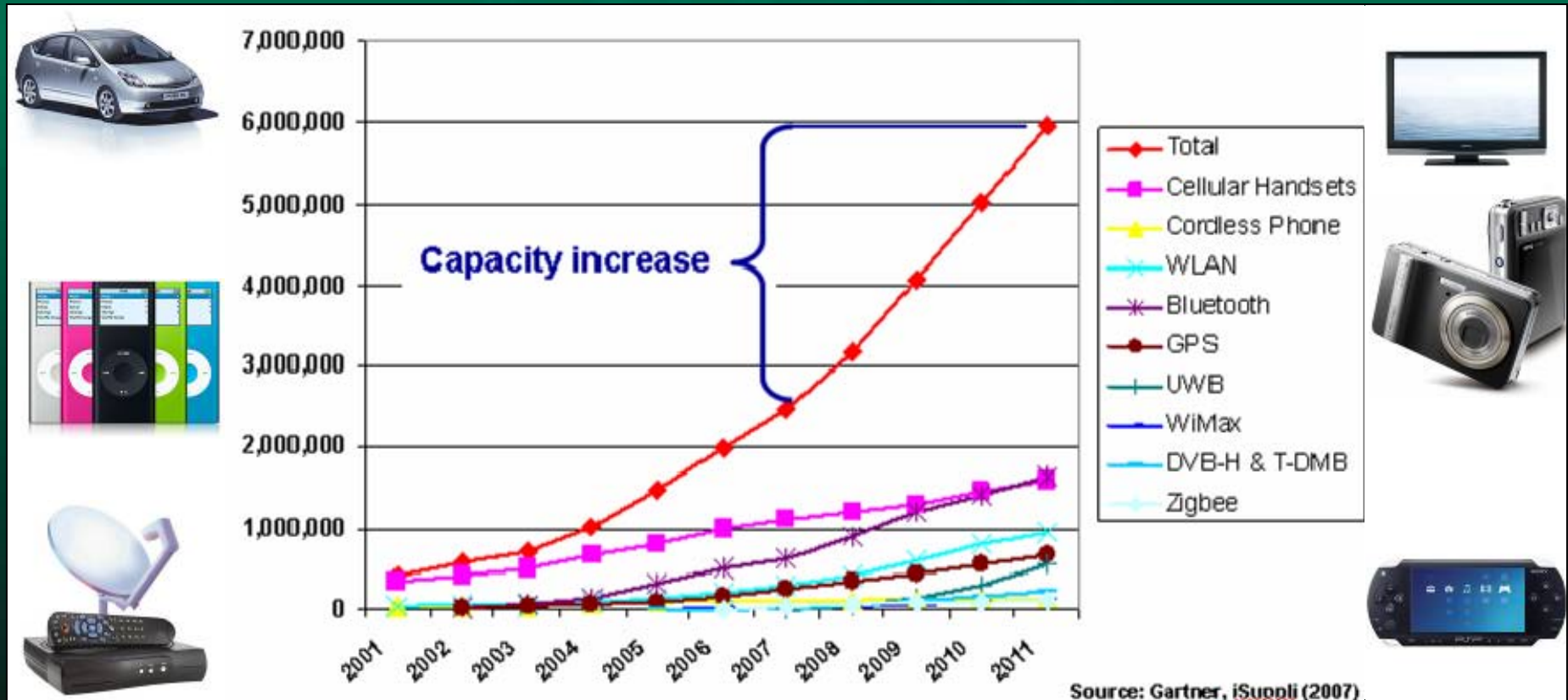
June 7-10, 2009  
San Diego, CA

Overcoming challenges  
of high multi-site, high multi-port  
RF wafer sort testing



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Mechanical Engineer  
Teradyne, Inc.

# Worldwide RF Semiconductor Market Trends: Strong Growth and integration into almost everything



RF Unit Volume

Device Complexity\*

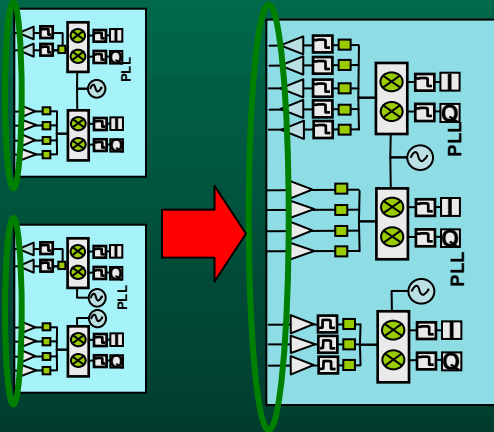
Product Life Cycles

ASP

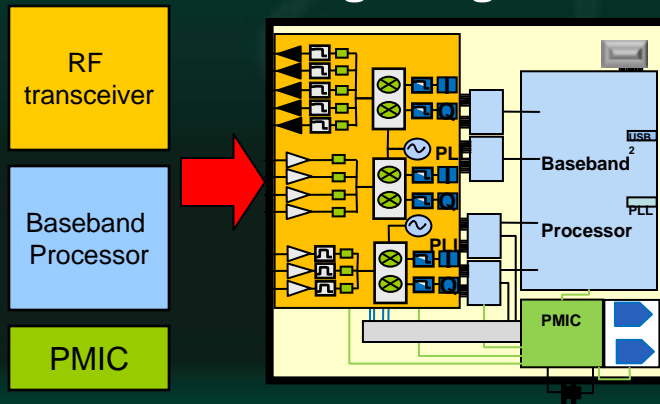


# Increasing Device Integration in RF and Digital impose design constraints

## Multi-mode Transceivers, MIMO



## RFSOC – Single Chip Radio & Analog Integration



### Complexity Impacts

- RF Port Count ↑
- Parallelism ↑
- Package Size ↓
- Digital Baseband ↑
- High Speed Serial ↑
- Test Time ↑
- ASP ↓

### Interface Design Challenges

- Increased Applications Space
- Higher RF mating forces
- High Digital Pin Force
- Signal Integrity
- Current Prober Capabilities
- COT - Leverage existing interface technology
- COT - Minimize interface circuit board cost



# What do we mean by high multi-site, high multi-port RF wafer sort testing?

## High Multi- Site:

- Above x2
- Up to X8 (and to X16 future)

## Digital Pins

- Greater than 2000 signal pins

## Multi-Port RF:

- Up to 16 RF Ports per device
- Low density = 24 RF Ports total
- Medium Density = 64 RF Ports total
- High Density = 96 RF Ports total

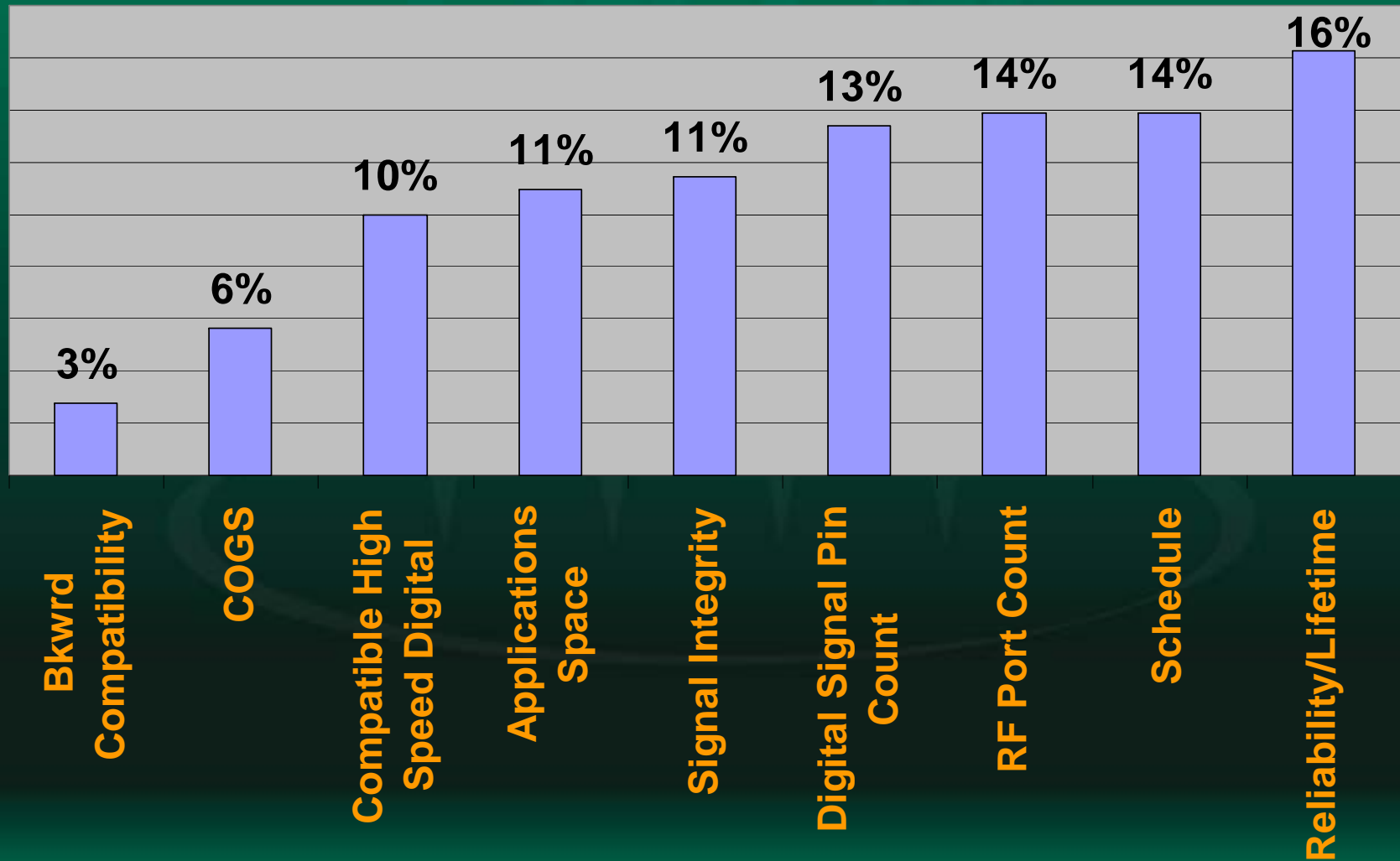


**Essentially, get 10 pounds of Wafer S#!T  
test into a 5 pound test interface bag...**

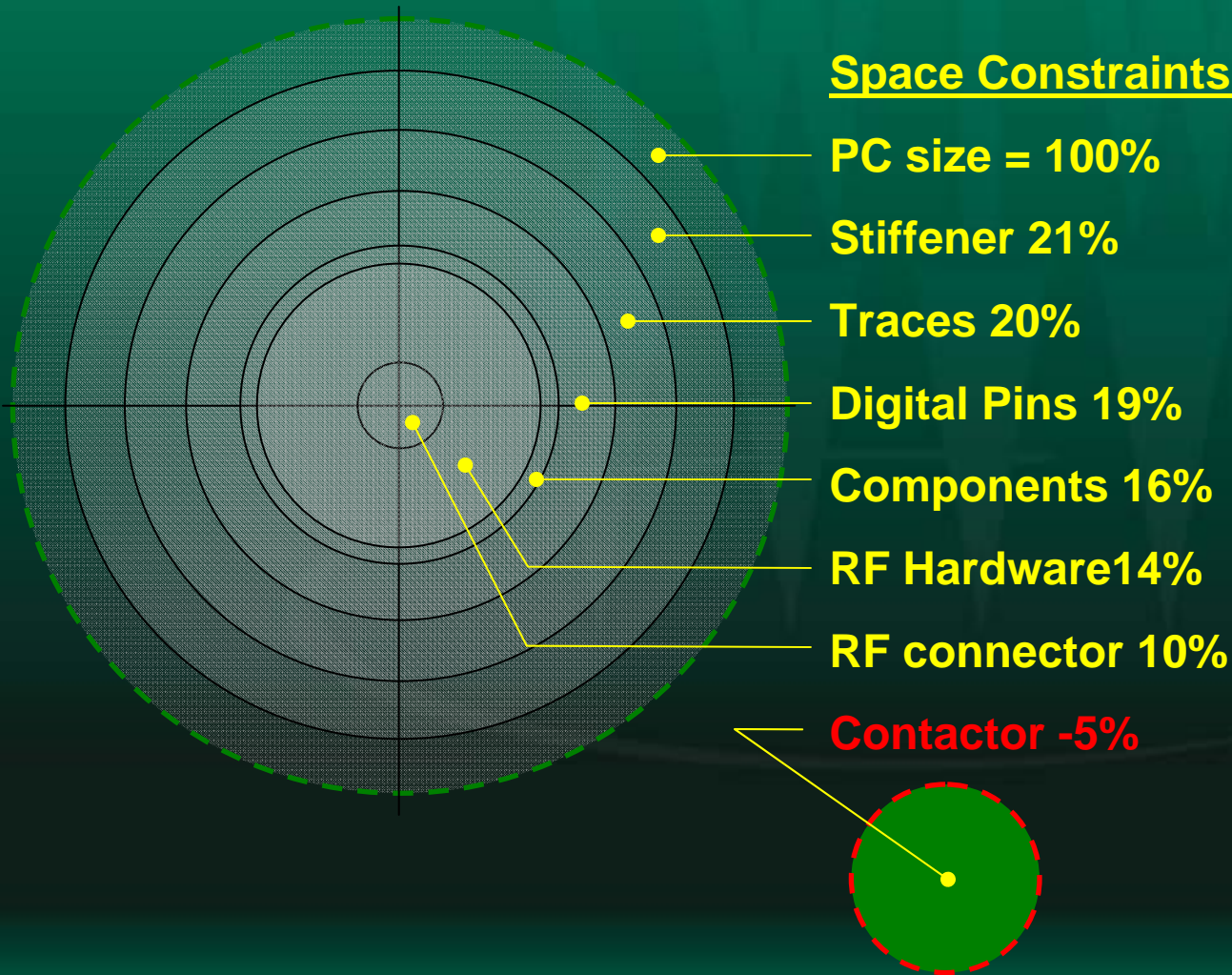


# Look at the entire RF interface as a system – define what is important so Intelligent Tradeoffs can be made...

## RF Probe: Criteria Weighting



# Applications Space – Some Applications can require more space than is available with 300mm hardware



## Space Constraints:

## Design Tradeoffs:

300/440 hardware

Deflection

RF vs. Digital Pin Count

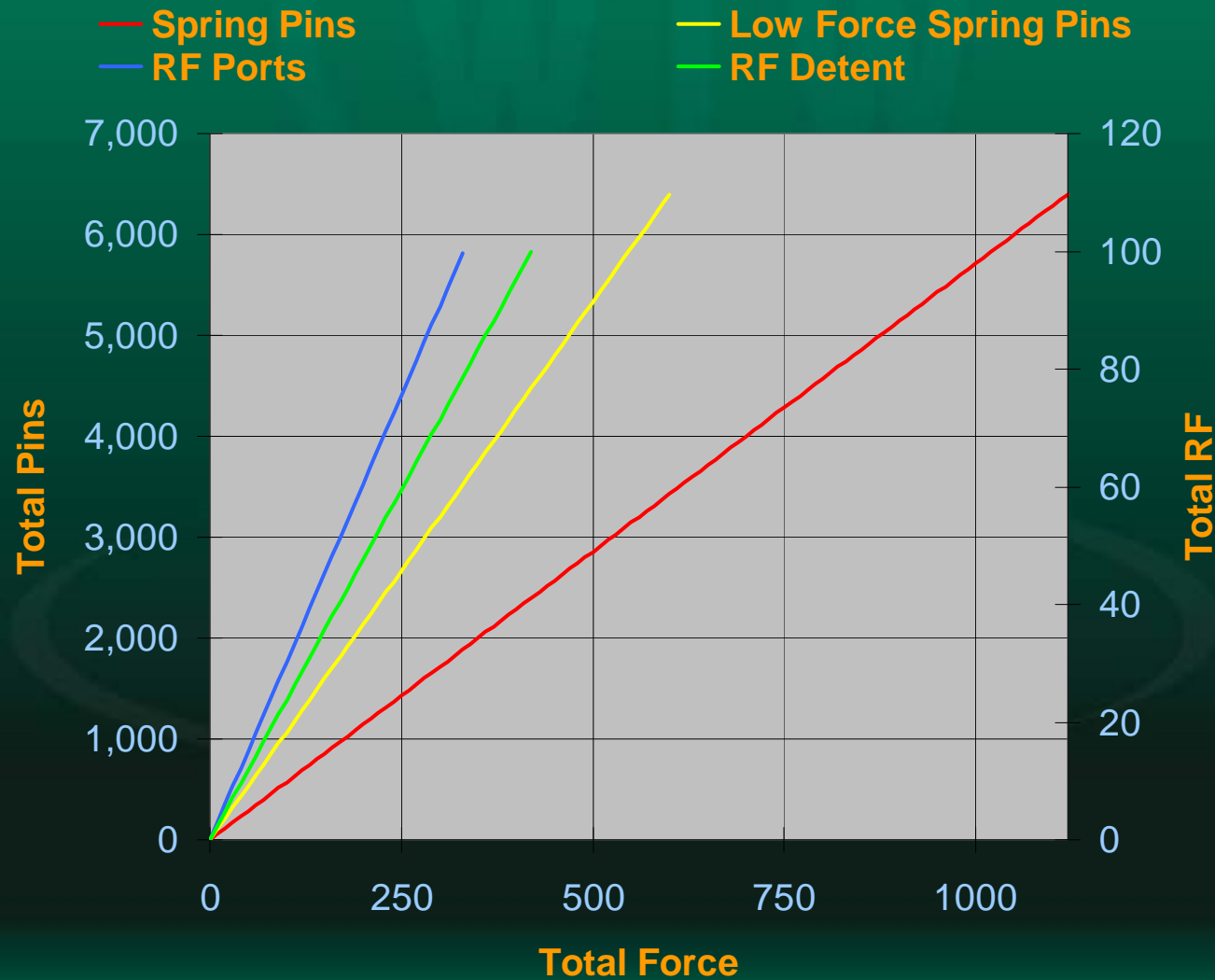
Cable Routing and bending

Signal integrity

Component placement



# RF Interface Forces Can overload interface components

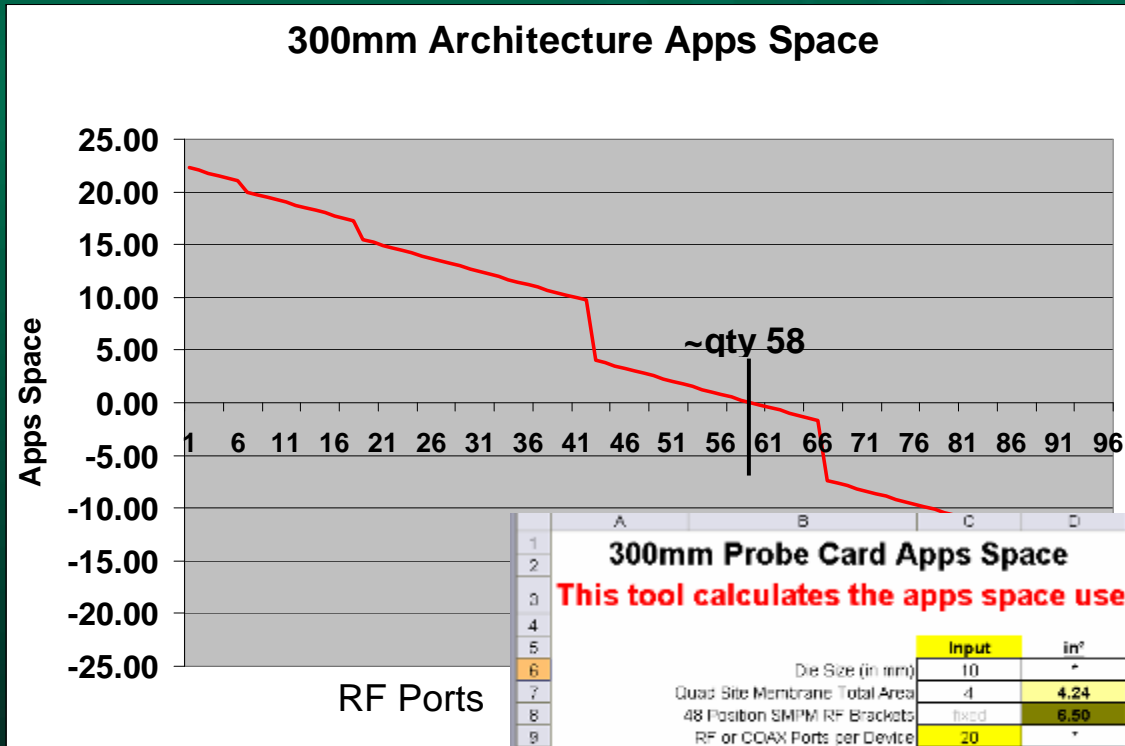




# Managing Applications Space

Build mathematical models of your applications space

- Stiffeners
- Traces
- Digital Pins
- Components
- Contactors
- Etc...



Include variables to manipulate the apps space tool for various what-if scenarios...

Evaluate tradeoffs.

**300mm Probe Card Apps Space**  
 This tool calculates the apps space used for RF

	Input	in <sup>2</sup>	
Die Size (in mm)	10	*	
Quad Site Membrane Total Area	4	4.24	
48 Position SMPM RF Brackets	fixed	6.50	
RF or COAX Ports per Device	20	*	96
SMPM Thru-Board and P/A connector .16" x .46"	fixed	9.14	18.72
Total RF ports per probe card	64	*	
0402 Components Qty	20	0.016	04 X .02
0603 components Qty	20	0.036	0.06 X .03
Other Components Qty			Need Size Data
Other Components Qty			Need Size Data
Traces, fencing vias, etc		0.000	Need Apps Data
3.141592654			
radius	1		
circular area	3.14		
<b>Apps space used by RF</b>		<b>19.94 in sq</b>	
300	11.81102362		

Signal Tower	Available Tower Apps Space	Probe Area Apps Space	Total Pins	Force (lbs)
Signal Tower Type	29.43	9.49	3,600	630

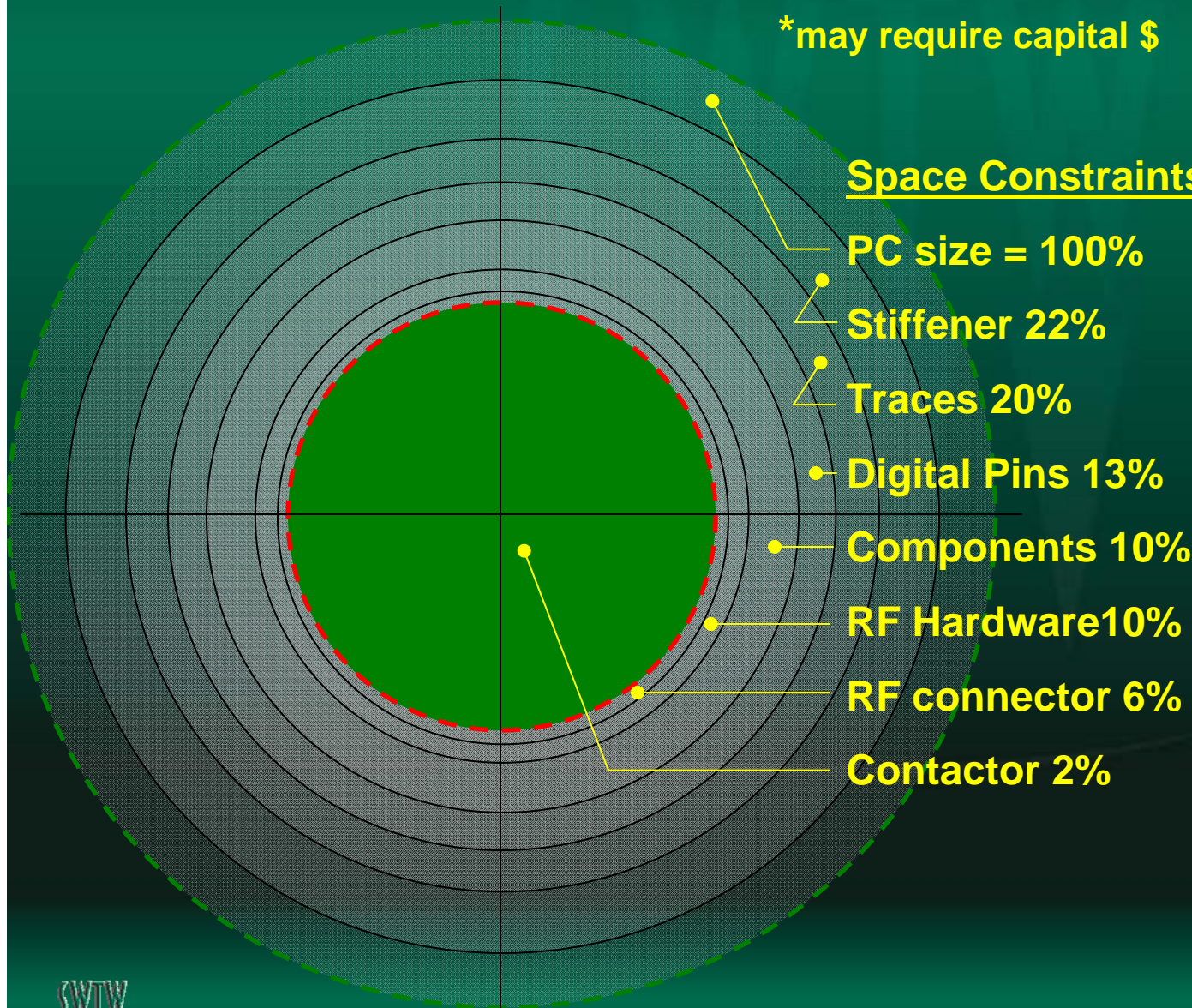
**300mm Application**



# Managing Applications Space

## Consider the Transition to 440mm Interfaces

\*may require capital \$



### Space Constraints:

PC size = 100%

Stiffener 22%

Traces 20%

Digital Pins 13%

Components 10%

RF Hardware 10%

RF connector 6%

Contactor 2%

### Design Tradeoffs:

300/440 hardware

Deflection

RF vs. Digital Pin Count

Cable Routing and bending

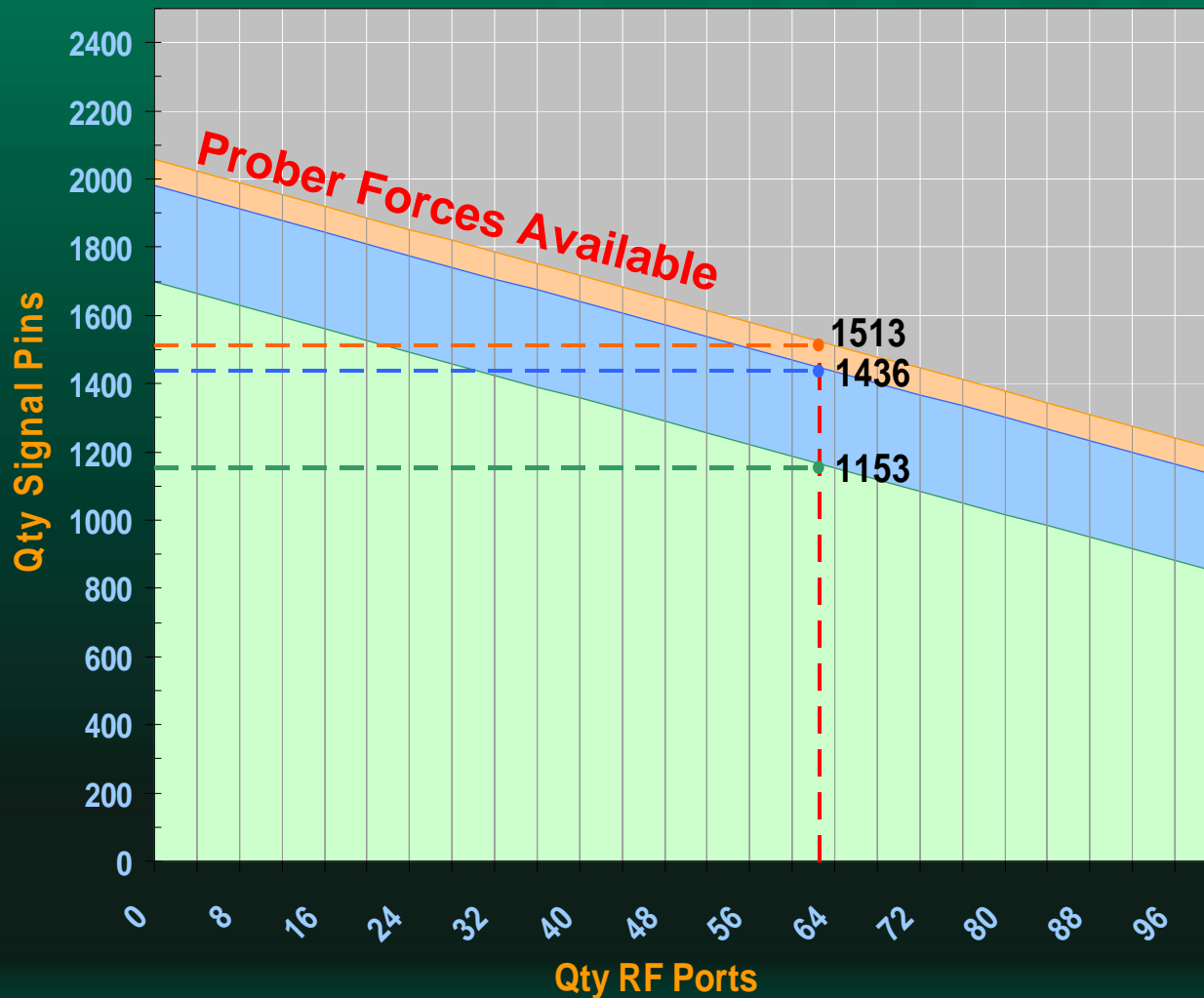
Signal integrity

Component placement



# Managing RF Interface Forces

Model and Understand the tradeoffs required to meet force constraints  
300mm Prober Forces - RF Ports vs Signal Pins Tradeoff



## Design Tradeoffs:

- Top Load vs. Bottom Load Interface Systems
- Bottom Probe Card Changer capacity
- Tester docking capacity
- Deflections
- RF vs. Digital Pin Count
- Don't forget un-mate forces...



PROBER1 PROBER2 PROBER3

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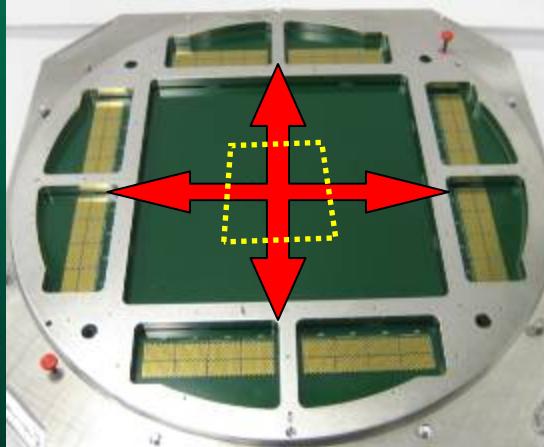
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# Managing RF Interface Forces

Maximizing applications space and minimizing probe card deflections

## 440mm Probe Card Stiffener

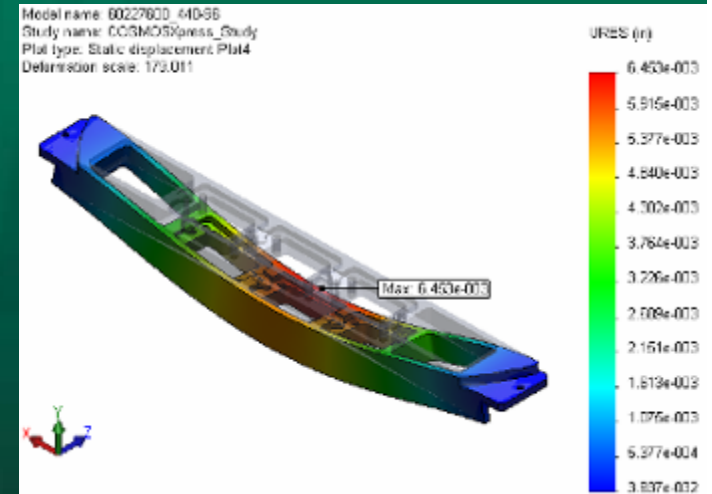


Digital pins and RF connections at perimeter

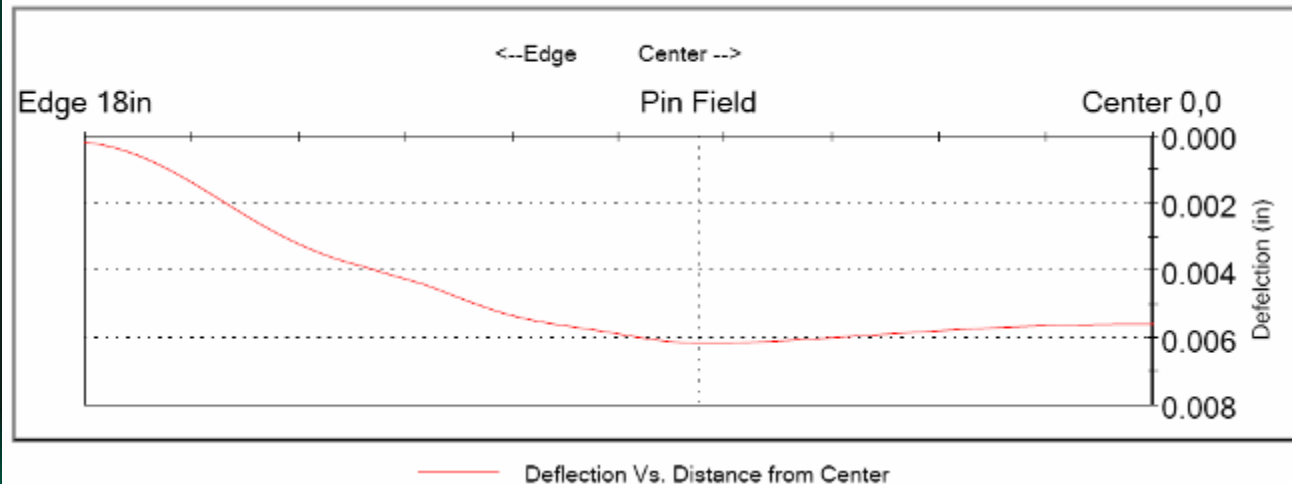
More apps space

More structure to minimize deflection

## 440mm Probe Card Deflection Profile



Deflection along axis from Center of PC to Outer Edge



## 440mm 96 Port RF hardware Deflection Study



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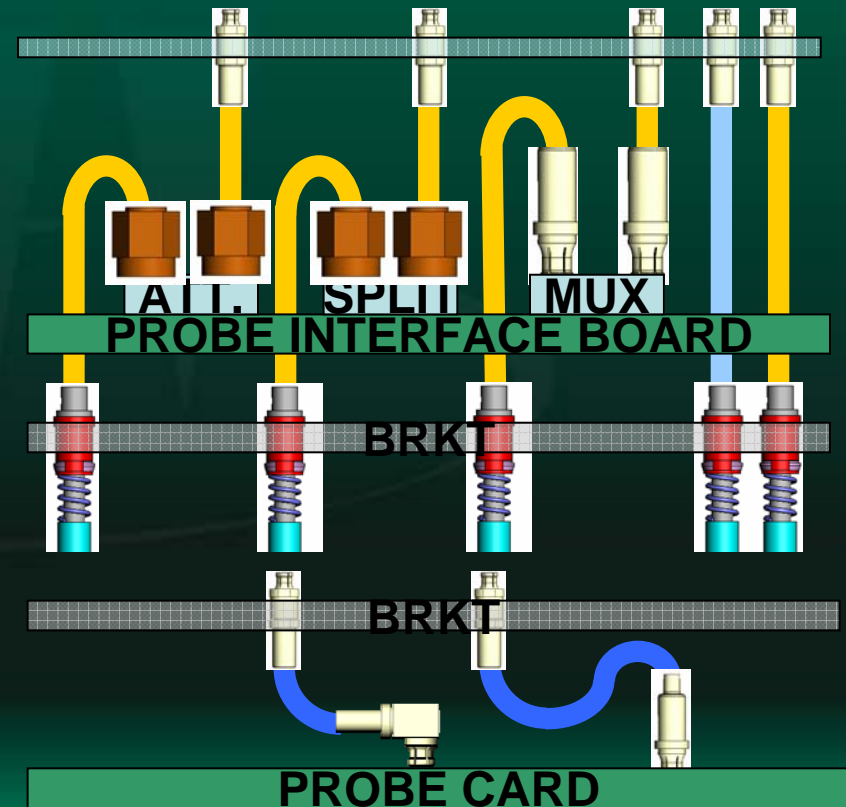
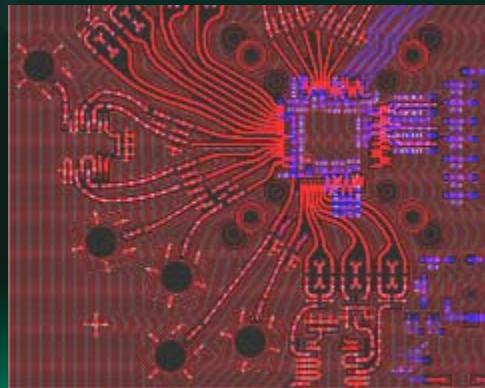
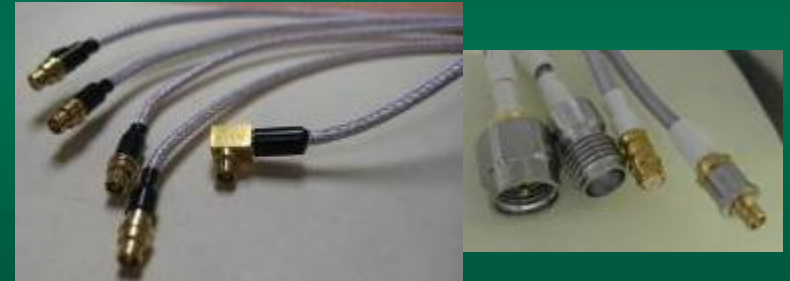
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# Maintaining RF Signal Integrity/Reliability

## Leverage existing technologies:

- Integrate with cable vendors to maximize performance while supporting required bend radii, cable diameter, connector options, etc...
- RF connector types (custom SMPM) have Proven signal Integrity, reliability
- Multiple connector styles allow application flexibility
- Support muxing, splitting, attenuation, etc.
- Allow active/passive component placement as close to DUT as possible

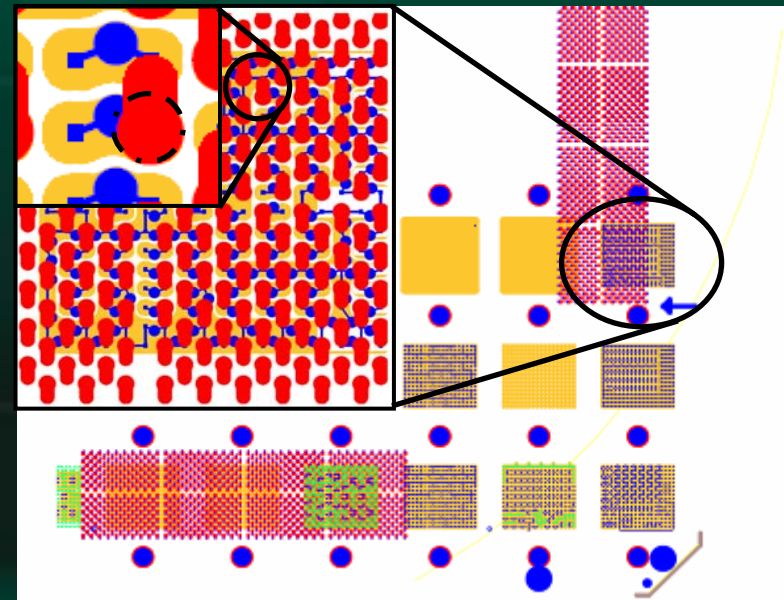
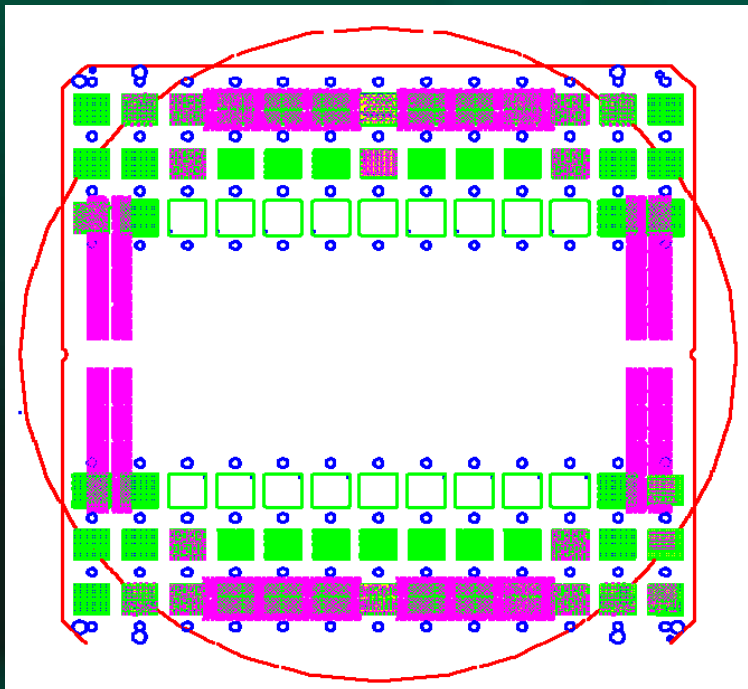


# COT – Managing Interface Circuit Board Design

Plan the board design with signal tower, apps space, and board routing integrated early.

Careful design and routing can facilitate pass through connections.

Avoid Blind Vias } Potential \$30% Savings  
Avoid Multi-layer Construction }



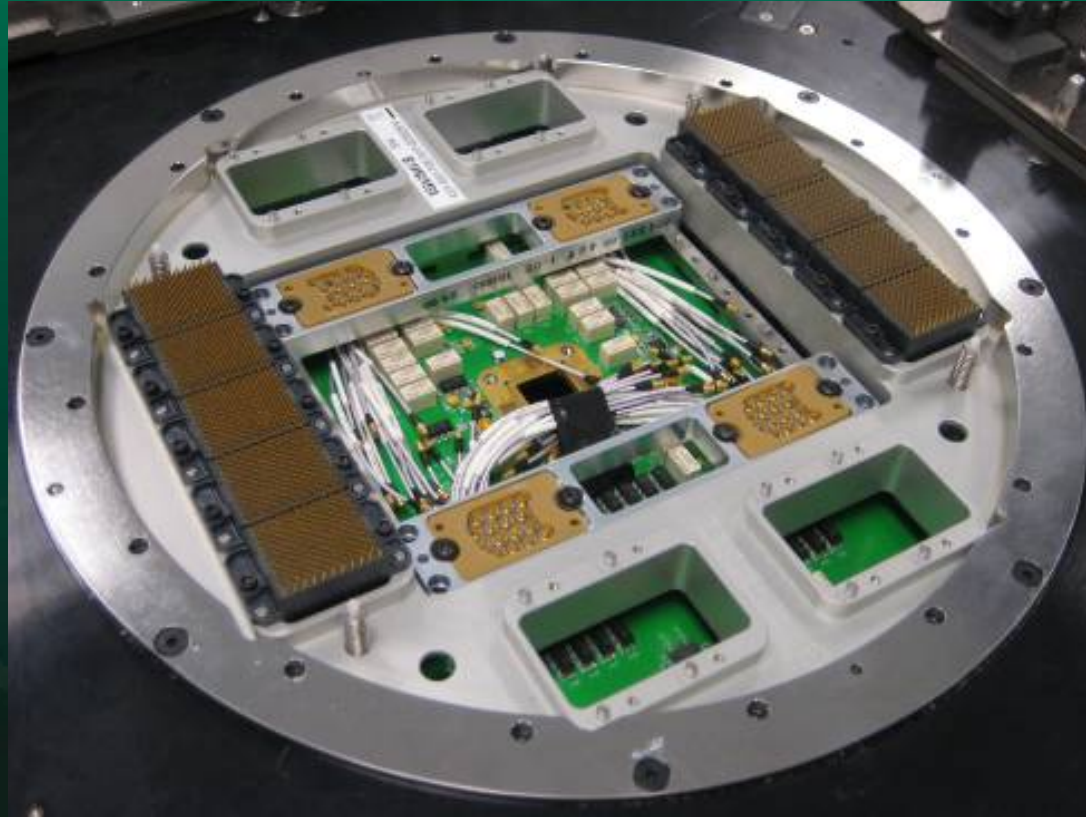
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# Real 300mm RF Hardware

300mm with 64 RF Ports 900 digital pins



You can still pack a lot of punch into a 300mm interface with careful planning



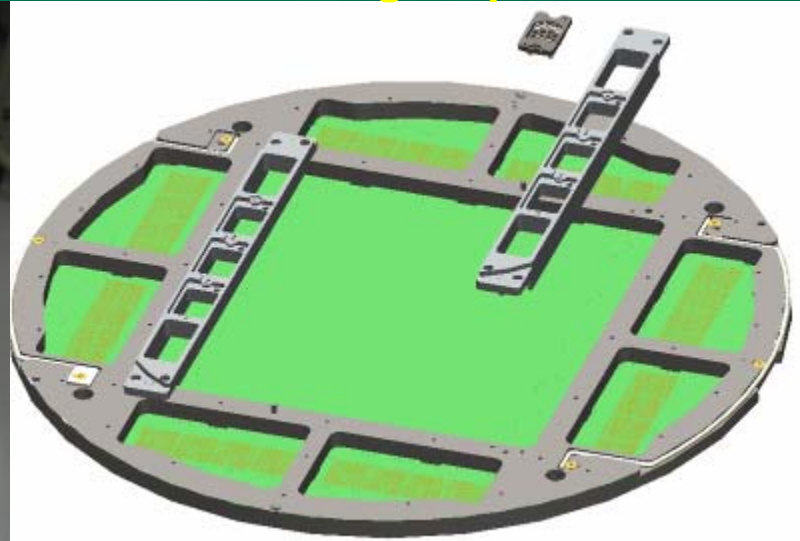
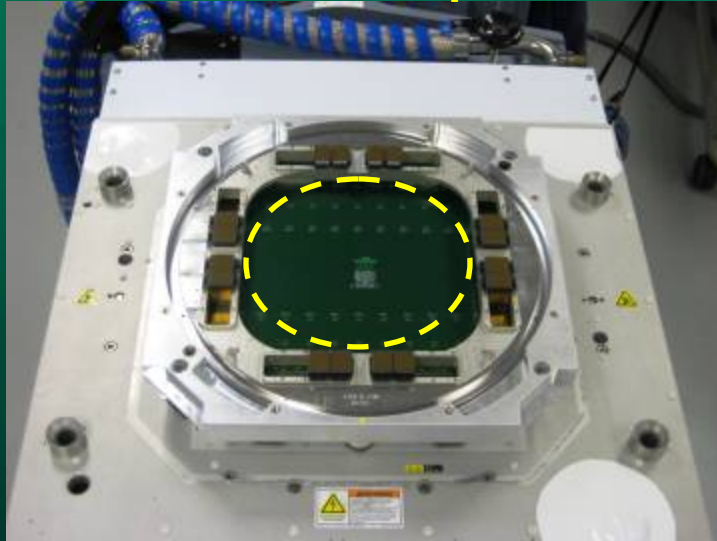
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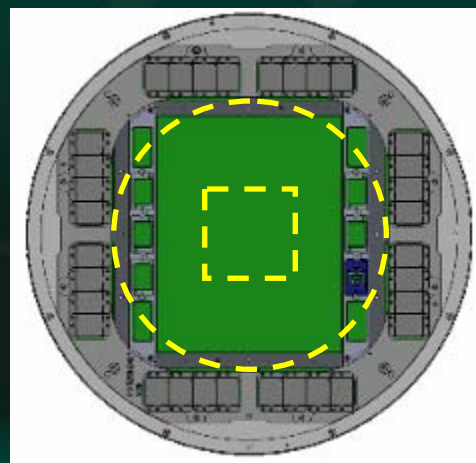
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# Real 440mm Solutions

440mm Probe Tower and Probe Card  
with up to 96 RF Ports and 2880 digital pins



20 inch chrome



20 inch pizza



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## In Conclusion...

- High density RF interface solutions pose some significant challenges, but are very manageable.
- Teradyne has done quite a bit of work to understand and define these challenges, and managed them to develop solutions that work.
- The key is to think big picture, act as a general contractor or system integrator.
- Learn the capabilities of the existing equipment technologies.
- Build tools that let you evaluate tradeoffs and investigate the variables of what-if scenarios.
- These challenges can be overcome with proper planning and careful implementation!

